RELIABILITY REPORT

FOR

MAX98500EWE+T

WAFER LEVEL PRODUCTS

June 10, 2011

MAXIM INTEGRATED PRODUCTS

120 SAN GABRIEL DR.

SUNNYVALE, CA 94086

Approved by
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Quality Assurance
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Conclusion

The MAX98500EWE+T successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards.

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I. Device Description

A. General

The MAX98500 is a high-efficiency Class D audio amplifier that features an integrated boost converter, to deliver a constant output power over a wide range of battery supply voltages. The boost converter operates at 2MHz, requiring only a small (2.2µH) external inductor and capacitor. The automatic level control has a battery tracking function that reduces the output swing as the supply voltage drops, preventing collapse of battery voltage. The amplifier has differential inputs and an internal fully differential design. The MAX98500 also features three gain settings (6dB, 15.5dB, and 20dB) that are selectable with a logic input. The MAX98500 is available in a small, 0.5mm pitch 16-bump WLP package (2.1mm x 2.1mm). It is specified over the extended -40°C to +85°C temperature range.

II. Manufacturing Information

A. Description/Function:	Boosted 2.2W Class D Amplifier with Automatic Level Control
B. Process:	S18
C. Number of Device Transistors:	20074
D. Fabrication Location:	California
E. Assembly Location:	Japan
F. Date of Initial Production:	April 24, 2010

III. Packaging Information

A. Package Type:	16-bump WLP 4x4 array
B. Lead Frame:	N/A
C. Lead Finish:	N/A
D. Die Attach:	None
E. Bondwire:	N/A (N/A mil dia.)
F. Mold Material:	None
G. Assembly Diagram:	#05-9000-4008
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard J-STD-020-C	Level 1
J. Single Layer Theta Ja:	°C/W
K. Single Layer Theta Jc:	°C/W
L. Multi Layer Theta Ja:	49°C/W
M. Multi Layer Theta Jc:	°C/W

IV. Die Information

A. Dimensions:	83.07 X 83.07 mils
B. Passivation:	Si_3N_4/SiO_2 (Silicon nitride/ Silicon dioxide)
C. Interconnect:	Al with Ti/TiN Barrier
D. Backside Metallization:	None
E. Minimum Metal Width:	0.18µm
F. Minimum Metal Spacing:	0.18µm
G. Bondpad Dimensions:	
H. Isolation Dielectric:	SiO_2
I. Die Separation Method:	Wafer Saw

V. Quality Assurance Information

A. Quality Assurance Contacts:	Richard Aburano (Manager, Reliability Engineering) Don Lipps (Manager, Reliability Engineering) Bryan Preeshl (Vice President of QA)
B. Outgoing Inspection Level:	0.1% for all electrical parameters guaranteed by the Datasheet. 0.1% For all Visual Defects.
C. Observed Outgoing Defect Rate:	< 50 ppm
D. Sampling Plan:	Mil-Std-105D

VI. Reliability Evaluation

A. Accelerated Life Test

The results of the 135°C biased (static) life test are shown in Table 1. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{MTTF} = \frac{1.83}{192 \times 4340 \times 45 \times 2}$$ (Chi square value for MTTF upper limit)

(where 4340 = Temperature Acceleration factor assuming an activation energy of 0.8eV)

$\lambda = 24.4 \times 10^{-9}$

λ = 24.4 F.I.T. (60% confidence level @ 25°C)

The following failure rate represents data collected from Maxim's reliability monitor program. Maxim performs quarterly life test monitors on its processes. This data is published in the Reliability Report found at http://www.maxim-ic.com/qa/reliability/monitor. Cumulative monitor data for the S18 Process results in a FIT Rate of 0.40 @ 25C and 6.96 @ 55C (0.8 eV, 60% UCL)

B. E.S.D. and Latch-Up Testing (lot SF7ZEQ002C, D/C 1009)

The AX28 die type has been found to have all pins able to withstand a transient pulse of

ESD-HBM:	+/- 2500V per JEDEC JESD22-A114
ESD-CDM:	+/- 750V per JEDEC JESD22-C101

Latch-Up testing has shown that this device withstands a current of +/- 100mA and overvoltage per JEDEC JESD78.

Table 1
Reliability Evaluation Test Results

MAX98500EWE+T

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES	COMMENTS
Static Life Test (Note 1)	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality	45	0	SF7ZDQ002C, D/C 1009

Note 1: Life Test Data may represent plastic DIP qualification lots.